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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re the Application of:

Hae-seok PARK et al.

Art Unit: 2862

Serial No. 10/763,394

Examiner: David M. Schindler

Filed: January 26, 2004

Confirmation No. 4583

For: FLUXGATE SENSOR INTEGRATED IN A  
SEMICONDUCTOR SUBSTRATE AND  
METHOD FOR MANUFACTURING THE  
SAME

Attorney Docket No. 277/044

**AMENDMENT IN RESPONSE TO QUAYLE ACTION**

Mail Stop: Amendment  
Commissioner for Patents  
United States Patent and Trademark Office  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

**INTRODUCTORY COMMENTS**

In response to the *Ex parte Quayle* Action mailed on September 25, 2006, the following amendments and remarks are respectfully submitted in connection with the above-identified application:

**Amendments to the Claims** are reflected in a listing of claims, which begins on page 2 of this paper.

**Remarks** begin on page 12 of this paper.